SURAGUS
Sensors & Instruments

EddyCus® TF inline RM – Resistivity Monitoring

P_T_inlineRM_21

Highlights

- Contact-free and realtime
- Accurate measurement
- High degree of variability and flexibility
  - In- and ex-vacuo solutions
  - Fixed sensor and traverse solutions
  - Single-lane and multi-lane solutions
- High sample rate up to 1,000 measurements per second

Sensor Series

- Sheet resistance (Ohm/sq)
- Metal layer thickness (nm, µm)
- Metal substrate thickness (µm)
- Anisotropy
- Defects
- Integrity assessment

Applications

- Wafer resistivity
- Ingot and boule resistivity
- Sputter target composition
- Purity assessment
- Electrical discharge machining
- Material sorting
- Melting, casting, sintering
- Defect imaging and integrity assessment

Materials

- Semiconductors
  - Si (mono, poly)
  - SiC, SiSiC
  - GaAs
  - GaN
- Alloys
- Metals
- Graphite
- Graphene
- Compounds
- Composites

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Visit us at:
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Engineered and Made in Germany

TÜV SÜD ISO 9001

JEC GROUP WINNER OF 2016 INNOVATION AWARD

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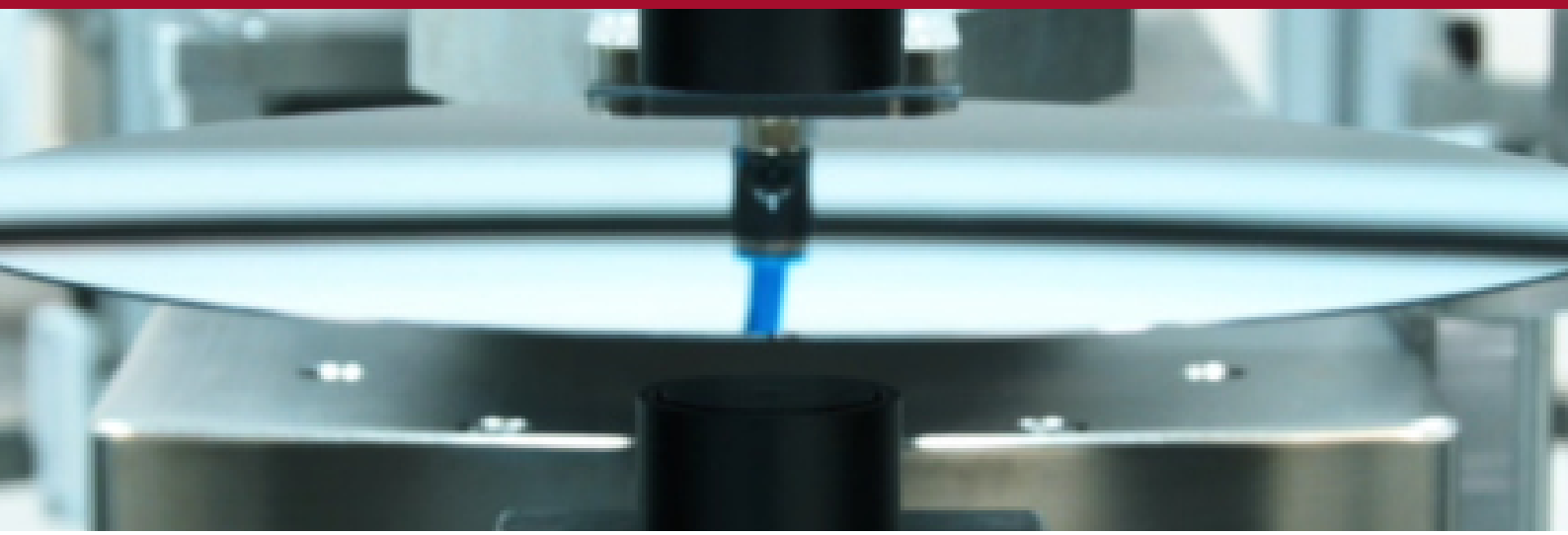

Measurement technology	High frequency eddy current sensor
Substrates	Wafer, metals, alloys, ceramics, plastics etc.
Materials	Semiconductors, metals, alloys, conductive polymers, conductive ceramics
Spot size	Various sensors are available. Coil size is 875 µm to 100 mm
Measurement gap size	5 / 10 / 15 / 25 / 50 / 75 mm
Number of sensor	1 – 99
Sensor sizes (W x L x H) in mm	Sensor M: 80 x 100 x 66 Sensor S: 34 x 48 x 117
Resistivity range	0.1 – 5,000 mOhm·cm
Conductivity range	0.01 – 65 MS/m
Environment	Ex-vacuo/ in-vacuo @ T < 60°C / 140°F (higher upon request)
Sample rate	1 / 10 / 50 / 100 / 1,000 measurements per second
Other integrated measurements	Metal thickness / optical transmittance / density / anisotropy
Hardware trigger	5 / 12 / 24 V
Interfaces	UDP, .Net libraries, TCP, Modbus, analog/digital

Device Control and Software

- Several views and user levels
- Live view with upper and lower limits and alarm functions
- Analysis view providing statistics
- Can handle data of several thousands measurements per second
- Data storage into SQL database
- Customizable automatic data export (csv, txt, xls,...)
- Several smart functions (automated DB cleaning, self-reference etc.)
- Parameterizable I/O modules (triggering of actions or alarms)